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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	STM8A
Core Size	8-Bit
Speed	24MHz
Connectivity	CANbus, I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	52
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	6K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	-
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8af5289tay

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Table 14. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5300	TIM2	TIM2_CR1	TIM2 control register 1	0x00
0x00 5301		TIM2_IER	TIM2 interrupt enable register	0x00
0x00 5302		TIM2_SR1	TIM2 status register 1	0x00
0x00 5303		TIM2_SR2	TIM2 status register 2	0x00
0x00 5304		TIM2_EGR	TIM2 event generation register	0x00
0x00 5305		TIM2_CCMR1	TIM2 capture/compare mode register 1	0x00
0x00 5306		TIM2_CCMR2	TIM2 capture/compare mode register 2	0x00
0x00 5307		TIM2_CCMR3	TIM2 capture/compare mode register 3	0x00
0x00 5308		TIM2_CCER1	TIM2 capture/compare enable register 1	0x00
0x00 5309		TIM2_CCER2	TIM2 capture/compare enable register 2	0x00
0x00 530A		TIM2_CNTRH	TIM2 counter high	0x00
0x00 530B		TIM2_CNTRL	TIM2 counter low	0x00
00 530C0x		TIM2_PSCR	TIM2 prescaler register	0x00
0x00 530D		TIM2_ARRH	TIM2 auto-reload register high	0xFF
0x00 530E		TIM2_ARRL	TIM2 auto-reload register low	0xFF
0x00 530F		TIM2_CCR1H	TIM2 capture/compare register 1 high	0x00
0x00 5310		TIM2_CCR1L	TIM2 capture/compare register 1 low	0x00
0x00 5311		TIM2_CCR2H	TIM2 capture/compare reg. 2 high	0x00
0x00 5312		TIM2_CCR2L	TIM2 capture/compare register 2 low	0x00
0x00 5313		TIM2_CCR3H	TIM2 capture/compare register 3 high	0x00
0x00 5314		TIM2_CCR3L	TIM2 capture/compare register 3 low	0x00
0x00 5315 to 0x00 531F	Reserved area (11 bytes)			

Table 14. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5320	TIM3	TIM3_CR1	TIM3 control register 1	0x00
0x00 5321		TIM3_IER	TIM3 interrupt enable register	0x00
0x00 5322		TIM3_SR1	TIM3 status register 1	0x00
0x00 5323		TIM3_SR2	TIM3 status register 2	0x00
0x00 5324		TIM3_EGR	TIM3 event generation register	0x00
0x00 5325		TIM3_CCMR1	TIM3 capture/compare mode register 1	0x00
0x00 5326		TIM3_CCMR2	TIM3 capture/compare mode register 2	0x00
0x00 5327		TIM3_CCER1	TIM3 capture/compare enable register 1	0x00
0x00 5328		TIM3_CNTRH	TIM3 counter high	0x00
0x00 5329		TIM3_CNTRL	TIM3 counter low	0x00
0x00 532A		TIM3_PSCR	TIM3 prescaler register	0x00
0x00 532B		TIM3_ARRH	TIM3 auto-reload register high	0xFF
0x00 532C		TIM3_ARRL	TIM3 auto-reload register low	0xFF
0x00 532D		TIM3_CCR1H	TIM3 capture/compare register 1 high	0x00
0x00 532E		TIM3_CCR1L	TIM3 capture/compare register 1 low	0x00
0x00 532F		TIM3_CCR2H	TIM3 capture/compare register 2 high	0x00
0x00 5330		TIM3_CCR2L	TIM3 capture/compare register 2 low	0x00
0x00 5331 to 0x00 533F	Reserved area (15 bytes)			
0x00 5340	TIM4	TIM4_CR1	TIM4 control register 1	0x00
0x00 5341		TIM4_IER	TIM4 interrupt enable register	0x00
0x00 5342		TIM4_SR	TIM4 status register	0x00
0x00 5343		TIM4_EGR	TIM4 event generation register	0x00
0x00 5344		TIM4_CNTR	TIM4 counter	0x00
0x00 5345		TIM4_PSCR	TIM4 prescaler register	0x00
0x00 5346		TIM4_ARR	TIM4 auto-reload register	0xFF
0x00 5347 to 0x00 53FF	Reserved area (185 bytes)			

Table 14. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5400	ADC	ADC _CSR	ADC control/status register	0x00
0x00 5401		ADC_CR1	ADC configuration register 1	0x00
0x00 5402		ADC_CR2	ADC configuration register 2	0x00
0x00 5403		ADC_CR3	ADC configuration register 3	0x00
0x00 5404		ADC_DRH	ADC data register high	0xXX
0x00 5405		ADC_DRL	ADC data register low	0xXX
0x00 5406		ADC_TDRH	ADC Schmitt trigger disable register high	0x00
0x00 5407		ADC_TDRL	ADC Schmitt trigger disable register low	0x00
0x00 5408 to 0x00 541F	Reserved area (24 bytes)			
0x00 5420	beCAN	CAN_MCR	CAN master control register	0x02
0x00 5421		CAN_MSR	CAN master status register	0x02
0x00 5422		CAN_TSR	CAN transmit status register	0x00
0x00 5423		CAN_TPR	CAN transmit priority register	0x0C
0x00 5424		CAN_RFR	CAN receive FIFO register	0x00
0x00 5425		CAN_IER	CAN interrupt enable register	0x00
0x00 5426		CAN_DGR	CAN diagnosis register	0x0C
0x00 5427		CAN_FPSR	CAN page selection register	0x00
0x00 5428		CAN_P0	CAN paged register 0	0xXX(3)
0x00 5429		CAN_P1	CAN paged register 1	0xXX(3)
0x00 542A		CAN_P2	CAN paged register 2	0xXX(3)
0x00 542B		CAN_P3	CAN paged register 3	0xXX(3)
0x00 542C		CAN_P4	CAN paged register 4	0xXX(3)
0x00 542D		CAN_P5	CAN paged register 5	0xXX(3)
0x00 542E		CAN_P6	CAN paged register 6	0xXX(3)
0x00 542F		CAN_P7	CAN paged register 7	0xXX(3)
0x00 5430		CAN_P8	CAN paged register 8	0xXX(3)
0x00 5431		CAN_P9	CAN paged register 9	0xXX(3)
0x00 5432		CAN_PA	CAN paged register A	0xXX(3)
0x00 5433		CAN_PB	CAN paged register B	0xXX(3)
0x00 5434		CAN_PC	CAN paged register C	0xXX(3)
0x00 5435		CAN_PD	CAN paged register D	0xXX(3)
0x00 5436		CAN_PE	CAN paged register E	0xXX(3)

Table 26. Total current consumption in Run, Wait and Slow mode. General conditions for V_{DD} apply, T_A = -40 °C to 150 °C

Symbol	Parameter	Conditions		Typ	Max	Unit
$I_{DD(RUN)}$(1)	Supply current in Run mode	All peripherals clocked, code executed from Flash program memory, HSE external clock (without resonator)	f_{CPU} = 24 MHz 1 ws	8.7	16.8(2)	mA
			f_{CPU} = 16 MHz	7.4	14	
			f_{CPU} = 8 MHz	4.0	7.4(2)	
			f_{CPU} = 4 MHz	2.4	4.1(2)	
			f_{CPU} = 2 MHz	1.5	2.5	
$I_{DD(RUN)}$(1)	Supply current in Run mode	All peripherals clocked, code executed from RAM, HSE external clock (without resonator)	f_{CPU} = 24 MHz	4.4	6.0(2)	
			f_{CPU} = 16 MHz	3.7	5.0	
			f_{CPU} = 8 MHz	2.2	3.0(2)	
			f_{CPU} = 4 MHz	1.4	2.0(2)	
			f_{CPU} = 2 MHz	1.0	1.5	
$I_{DD(WFI)}$(1)	Supply current in Wait mode	CPU stopped, all peripherals off, HSE external clock	f_{CPU} = 24 MHz	2.4	3.1(2)	
			f_{CPU} = 16 MHz	1.65	2.5	
			f_{CPU} = 8 MHz	1.15	1.9(2)	
			f_{CPU} = 4 MHz	0.90	1.6(2)	
			f_{CPU} = 2 MHz	0.80	1.5	
$I_{DD(SLOW)}$(1)	Supply current in Slow mode	f_{CPU} scaled down, all peripherals off, code executed from RAM	External clock 16 MHz f_{CPU} = 125 kHz	1.50	1.95	
			LSI internal RC f_{CPU} = 128 kHz	1.50	1.80(2)	

1. The current due to I/O utilization is not taken into account in these values.
2. Guaranteed by design, not tested in production.

Table 27. Total current consumption in Halt and Active-halt modes. General conditions for V_{DD} applied. T_A = -40 °C to 55 °C unless otherwise stated

Symbol	Parameter	Conditions			Typ	Max	Unit
		Main voltage regulator (MVR)(1)	Flash mode(2)	Clock source and temperature condition			
$I_{DD(H)}$	Supply current in Halt mode	Off	Power-down	Clocks stopped	5	35(3)	µA
				Clocks stopped, T_A = 25 °C	5	25	
$I_{DD(AH)}$	Supply current in Active-halt mode with regulator on	On	Power-down	External clock 16 MHz f_{MASTER} = 125 kHz	770	900(3)	
				LSI clock 128 kHz	150	230(3)	
	Supply current in Active-halt mode with regulator off	Off	Power-down	LSI clock 128 kHz	25	42(3)	
				LSI clock 128 kHz, T_A = 25 °C	25	30	
$t_{WU(AH)}$	Wakeup time from Active-halt mode with regulator on	On	Operating mode	T_A = -40 to 150 °C	10	30(3)	µs
	Wakeup time from Active-halt mode with regulator off	Off			50	80(3)	

1. Configured by the REGAH bit in the CLK_ICKR register.
2. Configured by the AHALT bit in the FLASH_CR1 register.
3. Guaranteed by characterization results, not tested in production.

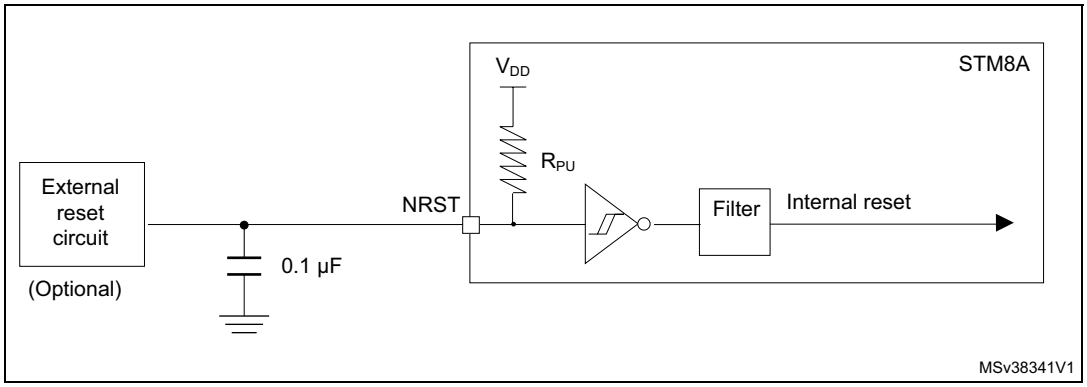
Current consumption for on-chip peripherals

Table 28. Oscillator current consumption

Symbol	Parameter	Conditions		Typ	Max(1)	Unit
$I_{DD(OSC)}$	HSE oscillator current consumption(2)	Quartz or ceramic resonator, CL = 33 pF V_{DD} = 5 V	f_{OSC} = 24 MHz	1	2.0(3)	mA
			f_{OSC} = 16 MHz	0.6	-	
			f_{OSC} = 8 MHz	0.57	-	
$I_{DD(OSC)}$	HSE oscillator current consumption(2)	Quartz or ceramic resonator, CL = 33 pF V_{DD} = 3.3 V	f_{OSC} = 24 MHz	0.5	1.0(3)	
			f_{OSC} = 16 MHz	0.25	-	
			f_{OSC} = 8 MHz	0.18	-	

1. During startup, the oscillator current consumption may reach 6 mA.
2. The supply current of the oscillator can be further optimized by selecting a high quality resonator with small R_m value. Refer to crystal manufacturer for more details
3. Informative data.

Figure 39. Recommended reset pin protection



10.3.8 TIM 1, 2, 3, and 4 electrical specifications

Subject to general operating conditions for V_{DD}, f_{MASTER} and T_A.

Table 40. TIM 1, 2, 3, and 4 electrical specifications

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{EXT}	Timer external clock frequency(1)	-	-	-	24	MHz

1. Not tested in production.

10.3.12 EMC characteristics

Susceptibility tests are performed on a sample basis during product characterization.

Functional EMS (electromagnetic susceptibility)

While executing a simple application (toggling 2 LEDs through I/O ports), the product is stressed by two electromagnetic events until a failure occurs (indicated by the LEDs).

- ***ESD***: Electrostatic discharge (positive and negative) is applied on all pins of the device until a functional disturbance occurs. This test conforms with the IEC 1000-4-2 standard.
- ***FTB***: A burst of fast transient voltage (positive and negative) is applied to V_{DD} and V_{SS} through a 100 pF capacitor, until a functional disturbance occurs. This test conforms with the IEC 1000-4-4 standard.

A device reset allows normal operations to be resumed. The test results are given in the table below based on the EMS levels and classes defined in application note AN1709.

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical data corruption (control registers...)

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be recovered by applying a low state on the NRST pin or the oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Table 45. EMS data

Symbol	Parameter	Conditions	Level/class
V_{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 3.3 V, T_A= 25 °C, f_{MASTER} = 16 MHz (HSI clock), Conforms to IEC 1000-4-2	3/B
V_{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V_{DD} and V_{SS} pins to induce a functional disturbance	V_{DD}= 3.3 V, T_A= 25 °C, f_{MASTER} = 16 MHz (HSI clock), Conforms to IEC 1000-4-4	4/A

Table 51. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.500	-	-	0.2165	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.500	-	-	0.2165	-
e	-	0.500	-	-	0.0197	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.080	-	-	0.0031

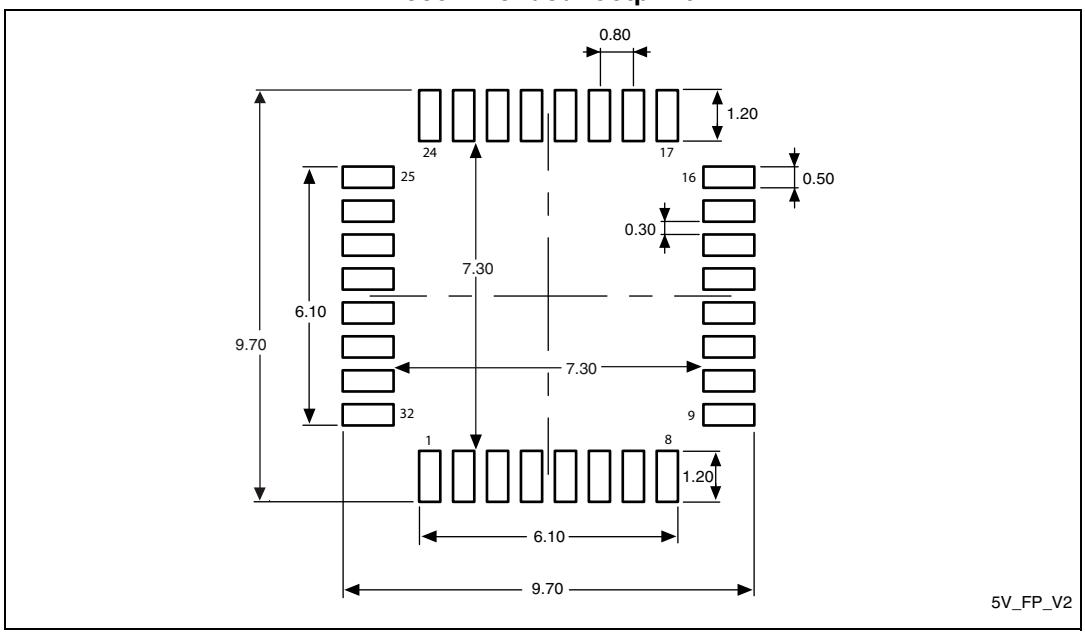
1. Values in inches are converted from mm and rounded to 4 decimal digits.

Table 52. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.300	0.370	0.450	0.0118	0.0146	0.0177
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.600	-	-	0.2205	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.600	-	-	0.2205	-
e	-	0.800	-	-	0.0315	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.100	-	-	0.0039

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 55. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package recommended footprint



1. Dimensions are expressed in millimeters.

Table 55. Document revision history (continued)

Date	Revision	Changes
30-Jan-2011	8	Modified references to reference manual, and Flash programming manual in the whole document. Added reference to AEC Q100 standard on cover page. Renamed timer types as follows: – Auto-reload timer to general purpose timer – Multipurpose timer to advanced control timer – System timer to basic timer Introduced concept of high density Flash program memory. Updated the number of I/Os for devices in 80-, 64-, and 48-pin packages in *Table: STM8AF52xx product line-up with CAN, Table: STM8AF62xx product line-up without CAN, Table: STM8AF/H/P51xx product line-up with CAN,* and *Table: STM8AF/H/P61xx product line-up without CAN.* Added TMU brief description in *Section 5.4: Flash program and data EEPROM*, updated TMU_MAXATT description in *Table 19: Option byte description*, and TMU_MAWATT reset value in *Table 18: Option bytes.* Updated clock sources in *Section 5.5.1: Features*. Added *Table 4: Peripheral clock gating bits (CLK_PCKENR1)*. Added calibration using TIM3 in *Section 5.7.2: Auto-wakeup counter.* Added *Table 8: ADC naming* and *Table 9: Communication peripheral naming correspondence*. Updated SPI data rate to $f_{MASTER}/2$ in *Section 5.9.3: Serial peripheral interface (SPI)*. Added reset state in *Table 10: Legend/abbreviation for the pin description table.* *Table: STM8A microcontroller family pin description:* modified footnotes related to PD1/SWIM, corrected wpu input for PE1 and PE2, and renamed TIMn_CCx and TIMn_NCCx to TIMn_CHx and TIMn_CHxN, respectively. *Section: Register map:* Removed CAN register CLK_CANCCR. Removed I2C_PECR register. Added *footnote* for Px_IDR registers in *Table 13: I/O port hardware register map*. Updated register reset values for Px_IDR and PD_CR1 registers. Replaced tables describing register maps and reset values for non-volatile memory, global configuration, reset status, TMU, clock controller, interrupt controller, timers, communication interfaces, and ADC, by *TTable 14: General hardware register map.* Added debug module register map Renamed Fast Active Halt mode to Active-halt mode with regulator on, and Slow Active Halt mode to Active-halt mode with regulator off, updated *Section 5.6: Low-power operating modes,* and *Table 27: Total current consumption in Halt and Active-halt modes. General conditions for VDD applied. TA = -40 °C to 55 °C unless otherwise stated.* $I_{DD(FAH)}$ and $I_{DD(SAH)}$ renamed $I_{DD(AH)}$; $t_{WU(FAH)}$ and $t_{WU(SAH)}$ renamed $t_{WU(AH)}$.